

C_TPLM40_65^{Q&As}

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QUESTION 1

QUESTION I
You cannot control inspection lot creation (lot combination) using he inspection type in the material master.
A. Incorrect
B. Correct
Correct Answer: A
QUESTION 2
The following inspection lots cannot be selected: Inspection lots with inspection point processing, SD inspection lots with partial lots, and inspection lots that require a digital signature.
A. Correct
B. Incorrect
Correct Answer: A
QUESTION 3
A material-dependent selection of defect codes cannot be planned.
A. Correct
B. Incorrect
Correct Answer: B
QUESTION 4
The dynamic modification rule defines the inspection stages and the conditions for an inspection stage change.
A. Correct
B. Incorrect
Correct Answer: A

QUESTION 5

QM is integrated in the processes of the logistics supply chain.

A. Correct



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B. Incorrect

Correct Answer: A

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